

IN THE  
UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor(s): Vahé Adamian

Serial No.:

Examiner:

Filing Date:

Group Art Unit:

Title: Method, Apparatus, and Article of Manufacture for Characterizing a Device and Predicting Electrical Behavior of the Device in a Circuit

COMMISSIONER FOR PATENTS  
PO Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

This Information Disclosure Statement is submitted:

- ☒ under 37 CFR 1.97(b), or  
(Within three months of filing national application; or date of entry of national application; or before mailing date of first office action on the merits; whichever occurs last)
- ☐ under 37 CFR 1.97(c) together with either a:  
☐ Statement under 37 CFR 1.97(e), or  
☐ a \$180.00 Processing fee under 37 CFR 1.17(p), or  
(After the 37 CFR 1.97 (b) time period, but before final action or notice of allowance, whichever occurs first)
- ☐ under 37 CFR 1.97 (d) together with a:  
☐ Statement under 37 CFR 1.97(e), and  
☐ a \$180.00 processing fee under 37 CFR 1.17(p).  
(Filed after final action or notice of allowance, whichever occurs first, but before payment of the issue fee)

Please charge to Deposit Account **50-1078** the sum of \$0.00. At any time during the pendency of this application, please charge any fees required or credit any overpayment to Deposit Account **50-1078** pursuant to 37 CFR 1.25.

☒ Applicant(s) submit herewith Form PTO 1449. References identified with an asterisk (\*) were disclosed in Patent Application No. 10/098,040 filed 3/14/2002, now U. S. Patent No. \_\_\_\_\_, and, as such, copies thereof are not included pursuant to the provisions of 37 CFR 1.98(d).

☐ A concise explanation of the relevance of foreign language patents, foreign language publications and other foreign language information listed on PTO Form 1449, as presently understood by the individuals(s) designated in 37 CFR 1.56 (c) most knowledgeable about the content is given on the attached sheet, or where a foreign language patent is cited in a search report or other action by a foreign patent office in a counterpart foreign application, an English language version of the search report or action which indicates the degree of relevance found by the foreign office is listed on form PTO 1449 and is enclosed herewith.

"Express Mail" label no.

Date of Deposit

I hereby certify that this is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" service under 37 CFR 1.10 on the date indicated above and is addressed to: Commissioner for Patents, PO Box 1450, Alexandria, VA 22313-1450.

By \_\_\_\_\_

Typed Name:

Respectfully submitted,

Vahé Adamian

By June L. Bouscaren  
June L. Bouscaren  
Attorney/Agent for Applicant(s)

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Date: Feb 17, 2004

Telephone No.: (970) 206-9177

<b>FORM PTO-1449</b>  <b>LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT</b>  (Use several sheets if necessary)	ATTY. DOCKET NO.	SERIAL NO.
	10020182-2	
	APPLICANT <b>Vahé Adamian</b>	
	FILING DATE	GROUP

## REFERENCE DESIGNATION

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	*	DOCUMENT NUMBER	DATE	NAME
	*	US20030135344	Jul 17, 2003	Martens
	*	6,300,775	10-2001	Peach et al.
	*	US20030173978	Sept 18, 2003	Adamian et al.
	*	5,025,402	Jun 18, 1991	Winkelstein
	*	US20030200039	Oct 23, 2003	Adamian et al.
	*	5,548,221	Aug 20, 1996	Adamian et al.
	*	6,106,563	Aug 22, 2000	Stengel et al.
	*	5,793,213	08-1998	Bockelman et al.
	*	5,537,046	07-1996	Adamian et al.
	*	6,539,344	03-2003	Stengel et al.

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	NAME	TRANSLATION	
					YES	NO

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

*	Agilent Technologies, Inc. Application Note entitled "De-embedding and Embedding S-Parameter Networks Using a Vector Network Analyzer", March 22, 2001
*	Bockelman and Eisenstadt, "Combined Differential and Common Mode Scattering Parameters: Theory and Simulation", IEEE Transactions on Microwave Theory and Techniques, Vol. 43, No. 7, July 1995
*	Bockelman, Eisenstadt, and Stengel, "Accuracy Estimation of Mixed Mode Scattering Parameter Measurements", IEEE Transactions on Microwave Theory and Techniques, Vol. 47, No. 1, January 1999

EXAMINER

DATE CONSIDERED

\* Copies of these references are not enclosed pursuant to 37 CFR 1.98(d). (See accompanying IDS)

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## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	*	DOCUMENT NUMBER	DATE	NAME
	*	US20020053899	May 9, 2002	Adamian et al.
	*	5,578,932	11/26/96	Adamian et al.
	*	5,434,511	7/18/95	Adamian et al.

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		DOCUMENT NUMBER	DATE	NAME	TRANSLATION	
					YES	NO

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

*	Bockelman and Eisenstadt, "Calibration and Verification of the Pure Mode Vector Network Analyzer", IEEE Transactions on Microwave Theory and Techniques, Vol. 46, No. 7, July 1998
*	Bockelman, Eisenstadt and Stengel, "Pure Mode Network Analyzer for On-Wafer Measurements of Mixed-Mode S-Parameters of Differential Circuits", "IEEE Transactions on Microwave Theory and Techniques, Vol. 45, No. 7, July 1997

EXAMINER	DATE CONSIDERED
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